

09980509_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 09980509 on July 11, 2003

Original Classifications

9 365/201
5 324/765
5 714/718
4 714/724
4 714/726
3 714/736
3 714/738
2 324/158.1
2 331/57
2 714/731
2 716/6

Cross-Reference Classifications

8 365/233
8 714/724
7 365/201
5 324/158.1
4 714/736
4 714/742
3 714/718
3 714/738
3 714/744
2 324/617
2 324/633
2 324/73.1
2 324/765
2 327/265
2 365/194
2 365/203
2 365/230.08
2 368/118
2 368/120
2 714/30
2 714/39
2 714/725
2 714/741
2 714/815
2 716/4

Combined Classifications

16 365/201
12 714/724
8 365/233

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8 714/718
7 324/158.1
7 324/765
7 714/736
6 714/738
4 714/726
4 714/742
3 714/731
3 714/744
2 324/617
2 324/633
2 324/73.1
2 327/265
2 331/57
2 365/189.05
2 365/194
2 365/203
2 365/230.08
2 368/118
2 368/120
2 714/30
2 714/39
2 714/723
2 714/725
2 714/741
2 714/743
2 714/815
2 716/4
2 716/6

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Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09980509 on July 11, 2003

16 365/201 (9 OR, 7 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/201 .Testing

12 714/724 (4 OR, 8 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing

8 365/233 (0 OR, 8 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/230.01 ADDRESSING
365/233 .Sync/clocking

8 714/718 (5 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/718 .Memory testing

7 324/158.1 (2 OR, 5 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/158.1 MISCELLANEOUS

7 324/765 (5 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/765 ..Test of semiconductor device

7 714/736 (3 OR, 4 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/736 ..Device response compared to expected
fault-free response

6 714/738 (3 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT

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DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/738 ..Including test pattern generator

4 714/726 (4 OR, 0 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))

4 714/742 (0 OR, 4 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/738 ..Including test pattern generator
714/742 ...Testing specific device

3 714/731 (2 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))
714/731 ...Clock or synchronization

3 714/744 (0 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/738 ..Including test pattern generator
714/744 ...Clock or synchronization

2 324/617 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
RELATIONSHIPS
324/612 .Parameter related to the reproduction or
fidelity of a signal affected by a circuit

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t under test

324/615 ..Transfer function type characteristics
324/617 ...Response time or phase delay

2 324/633 (0 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RES

PONSE

RELATIONSHIPS

324/629 .Distributive type parameters
324/633 ..Using resonant frequency

2 324/73.1 (0 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING
324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

2 327/265 (0 OR, 2 XR)

Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
327/261 .Having specific delay in producing output
waveform
327/263 ..Delay interval set by rising or falling edge
327/264 ...Having specific active circuit element or
structure (e.g., FET, complementary transi
stors, etc.)
327/265With counter

2 331/57 (2 OR, 0 XR)

Class 331 : OSCILLATORS
331/57 RING OSCILLATORS

2 365/189.05 (1 OR, 1 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/189.05 .Having particular data buffer or latch

2 365/194 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/191 .Signals
365/194 ..Delay

2 365/203 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT

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365/203

.Precharge

2 365/230.08 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL

365/230.01 ADDRESSING

365/230.08 .Including particular address buffer or latch
circuit arrangement

2 368/118 (0 OR, 2 XR)

Class 368 : HOROLOGY: TIME MEASURING SYSTEMS OR DEVICES

368/89 TIME INTERVAL

368/107 .Electrical or electromechanical

368/113 ..Stop time type

368/118 ...Including time base oscillator

2 368/120 (0 OR, 2 XR)

Class 368 : HOROLOGY: TIME MEASURING SYSTEMS OR DEVICES

368/89 TIME INTERVAL

368/107 .Electrical or electromechanical

368/113 ..Stop time type

368/120 ...Including delay means

2 714/30 (0 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/25 ..Fault locating (i.e., diagnosis or testing)

714/27 ...Particular access structure

714/30Built-in hardware for diagnosing or testin

g

or test mode
within-system component (e.g., microprocess
circuit, scan path)

2 714/39 (0 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/25 ..Fault locating (i.e., diagnosis or testing)

714/37 ...Analysis (e.g., of output, state, or design

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714/39      ....Monitor recognizes sequence of events
              (e.g., protocol or logic state analyzer)

2  714/723      (1 OR, 1 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/718      .Memory testing
714/723      ..Error mapping or logging

2  714/725      (0 OR, 2 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/724      .Digital logic testing
714/725      ..Programmable logic array (PLA) testing

2  714/741      (0 OR, 2 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/724      .Digital logic testing
714/738      ..Including test pattern generator
714/741      ...Simulation

2  714/743      (1 OR, 1 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/724      .Digital logic testing
714/738      ..Including test pattern generator
714/743      ...Addressing

2  714/815      (0 OR, 2 XR)
      Class 714 : ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
714/699      PULSE OR DATA ERROR HANDLING
714/799      .Error/fault detection technique
714/811      ..Forbidden combination or improper condition

714/815      ...Time delay/interval monitored

2  716/4        (0 OR, 2 XR)
      Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
                  CIRCUIT OR SEMICONDUCTOR MASK
716/1        CIRCUIT DESIGN

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	716/4	.Testing or evaluating
2	716/6	(2 OR, 0 XR)
	Class	716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
		CIRCUIT OR SEMICONDUCTOR MASK
	716/1	CIRCUIT DESIGN
	716/4	.Testing or evaluating
	716/5	..Design verification (e.g., wiring line
		capacitance, fan-out checking, minimum pat
h width)		
	716/6	...Timing analysis (e.g., delay time, path
		delay, latch timing)

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6317372 91
6175939 78
6553529 78
4775977 75
5499248 71
5794175 71
5606567 71
4893072 71
6144262 71
6195772 71
6232845 71
4631724 71
6049901 71
6119257 71
6223314 71
6223314 71
4477902 71
4608669 71
5177440 71
5195097 71
5268639 71
5325053 71
5351211 71
5357195 71
5432797 71
5734660 71
5757705 71
5872797 71
5969653 71
5995426 71
5996098 71
6097206 71
6104651 71
6114870 71
6157200 71
6158029 71
6201746 71
6226765 71
6226765 71
6253360 71
6255843 71
6275057 71
6275428 71
6298465 71
6360343 71
6374392 71
6377065 71
6400625 71

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6404218 71
6404684 71